

**10/587268**  
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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128865		APPLICATION NO. New U.S. National Phase of PCT/JP2005/001225	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Hiroaki TAKAIWA et al.			
				FILING DATE July 26, 2006			
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EXAMINER /Michael Liu/					DATE CONSIDERED 06/06/2008		
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